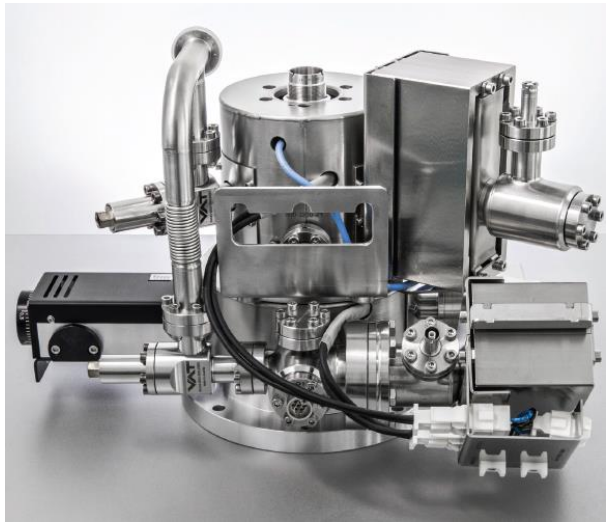
delong instruments®

. . . your way to electron microscopy



LVEM Introduction

LOW VOLTAGE ELECTRON MICROSCOPES FOR EVERY LAB

„Every scientist should have the opportunity to regularly use a transmission electron microscope for his or her research.“

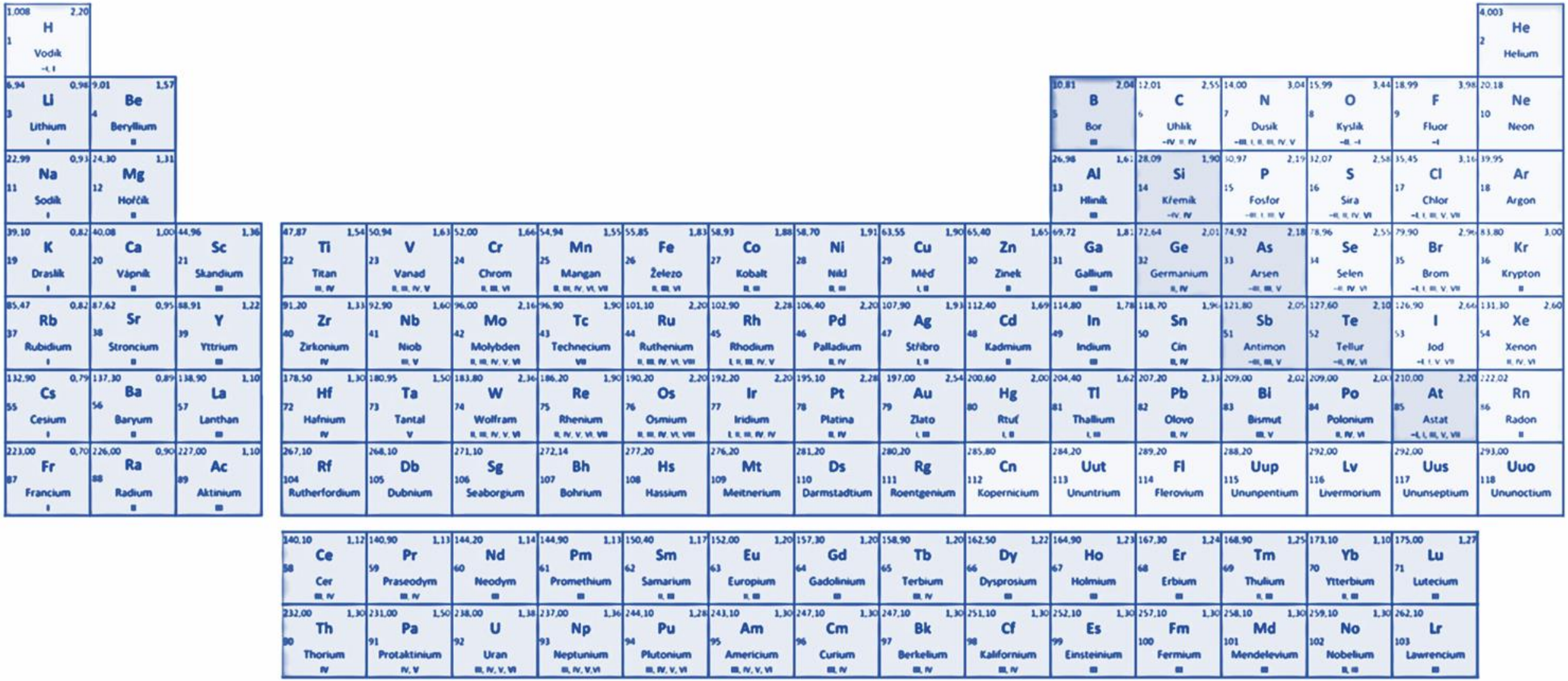
Prof. Armin Delong

founder of electron microscopy in Czechoslovakia


delong instruments
Powered by
DeLong Low Voltage Technology
LVEM 5


delong instruments
Powered by
Delong Low Voltage Technology
LVEM 25

LOW VOLTAGE TEM?



LVEM Advantages

High contrast with biologic and light material samples

- Lower necessity of staining
- Excellent for organic samples and nanomaterials

Suitability of permanent magnet lenses

- No water cooling
- Allowing miniaturisation

LVEM 5: Nanoscale from Your Benchtop

- Unique benchtop design
- Easy installation
- Simplified workflow
- Quick sample exchange
- Fast results
- Standard TEM grids
- Schottky FEG

LVEM 5: The World's Smallest TEM

Universal

- TEM
- SEM
- STEM
- ED

High resolution

- 1.2 nm TEM Boost
- 4 nm SEM
- 2.5 nm STEM

LVEM 25: Uncomplicated & Quick Results

- Compact design
- Easy installation
- Simplified software and intuitive controls
- High contrast
- Fast sample exchange
- Standard TEM grids
- Schottky FEG

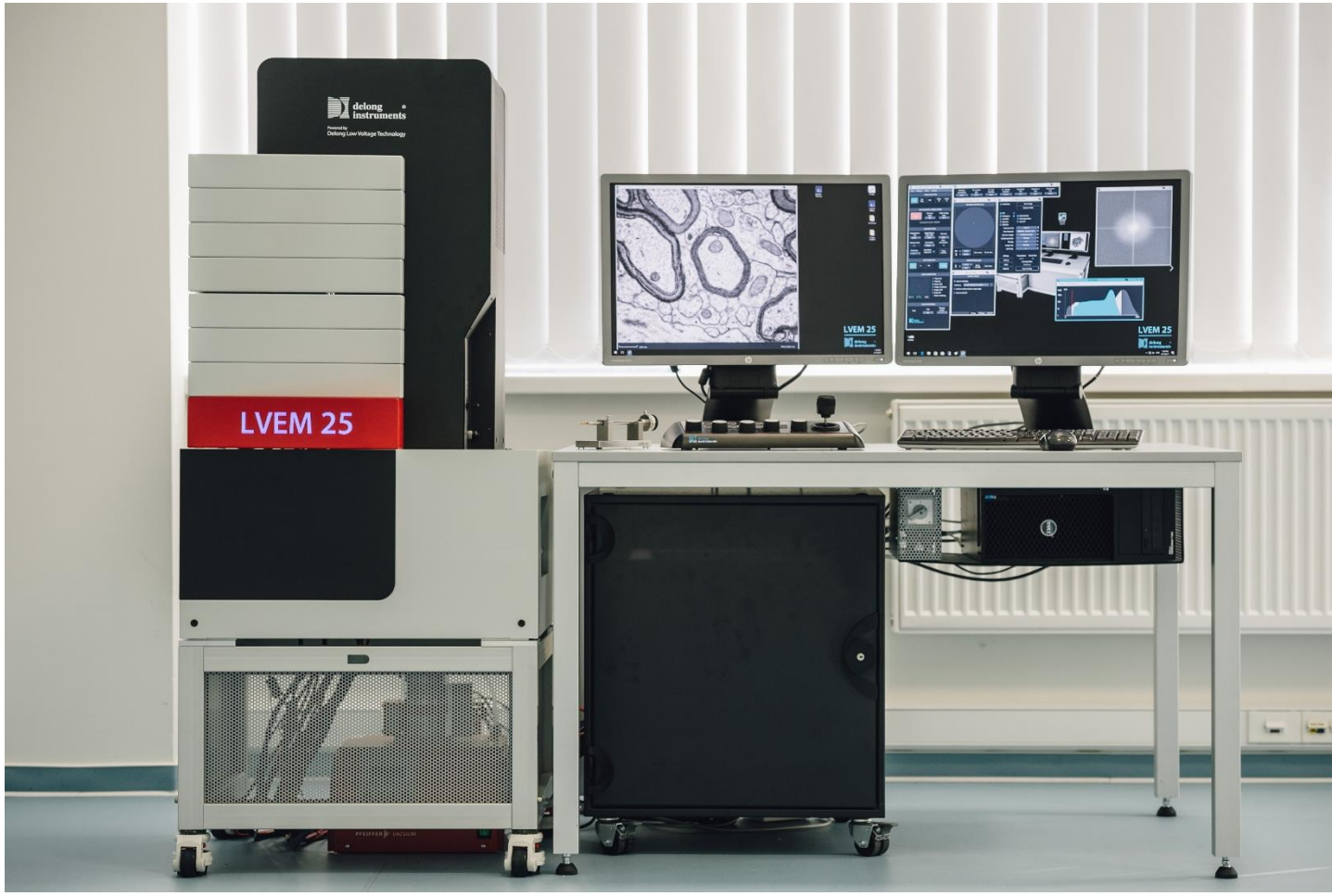
LVEM 25: Fast • Compact • Powerful

Compact

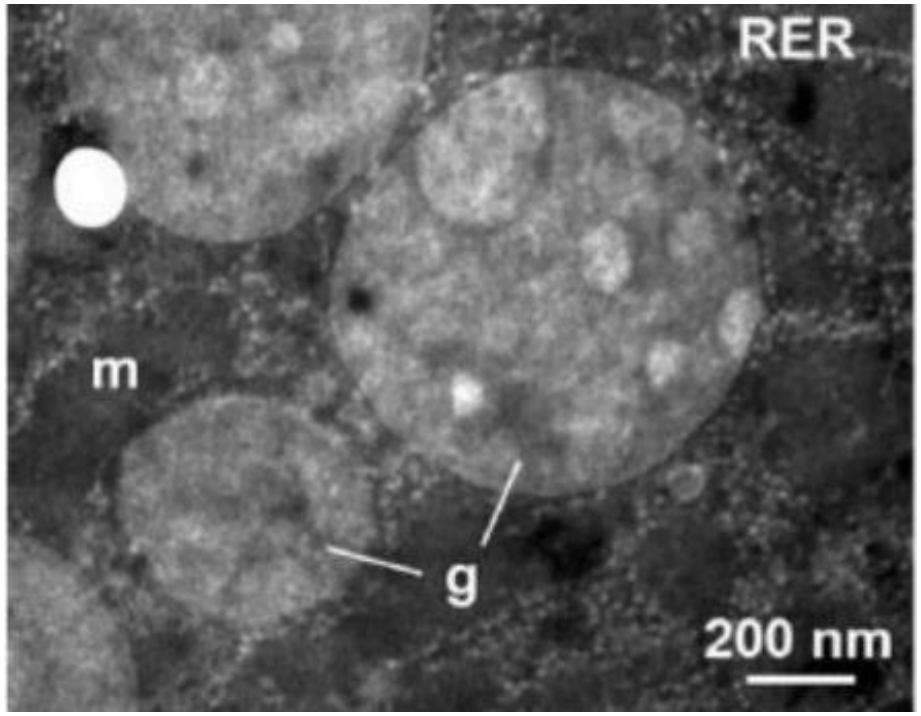
- TEM (25 kV)
- STEM (10 a 15 kV)
- ED

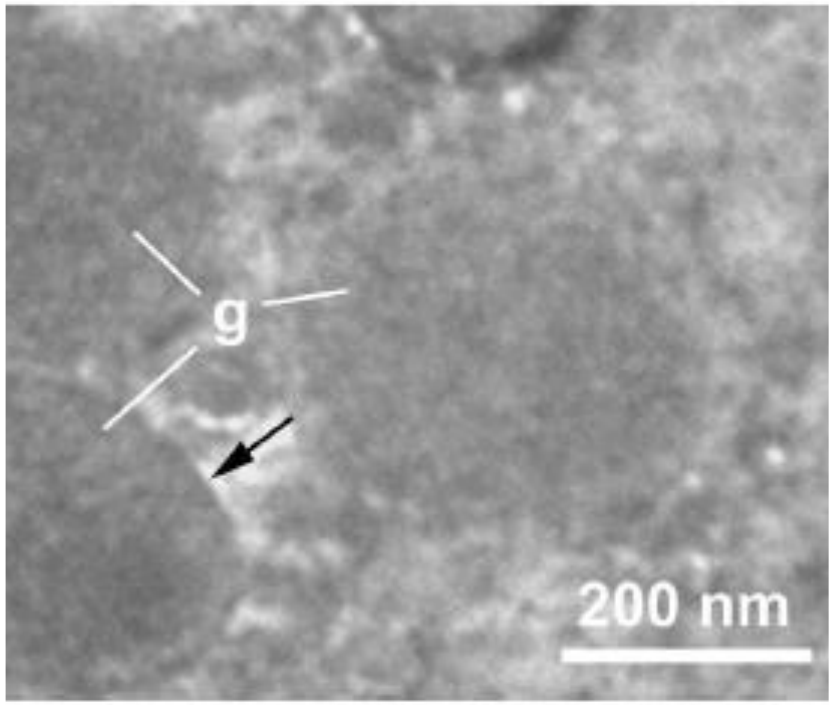
High resolution

- 1.0 nm TEM
- 1.0 nm STEM 10 kV
- 1.3 nm STEM 15 kV

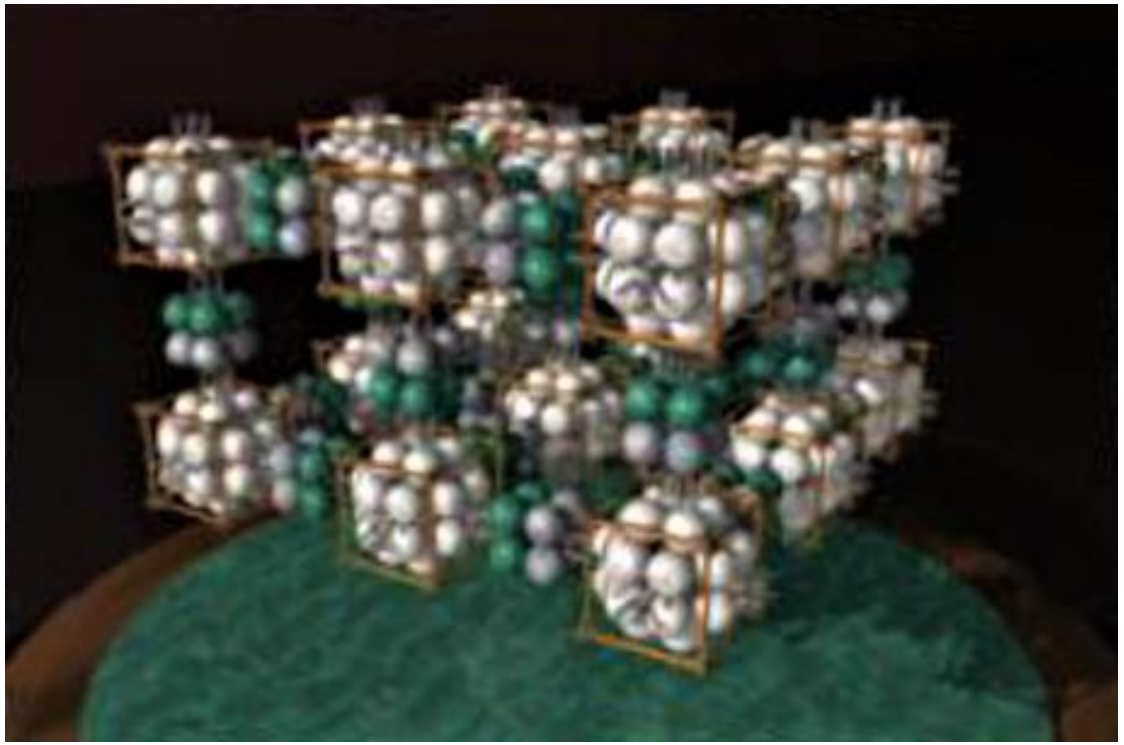


Where LVEMs Help

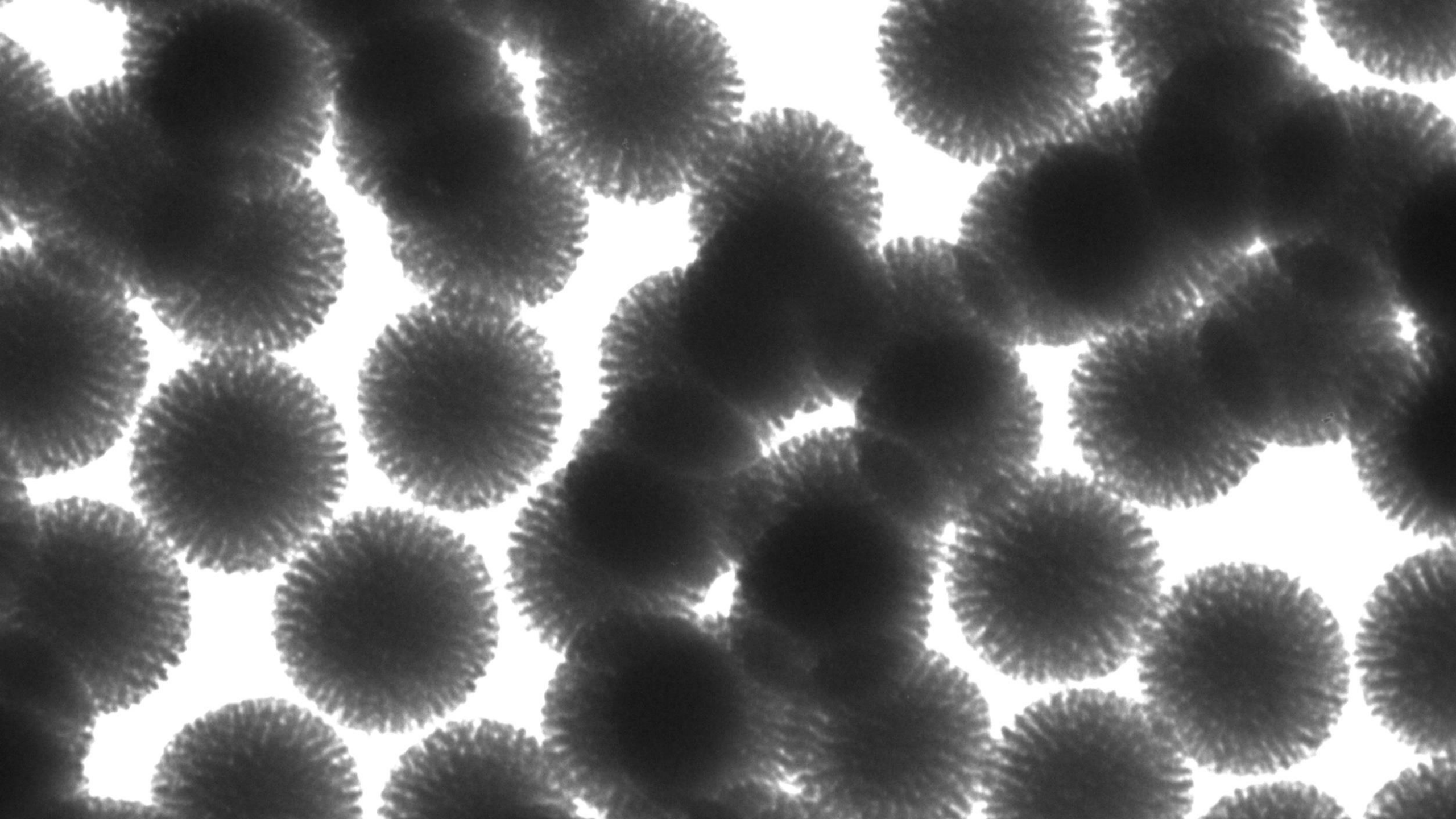


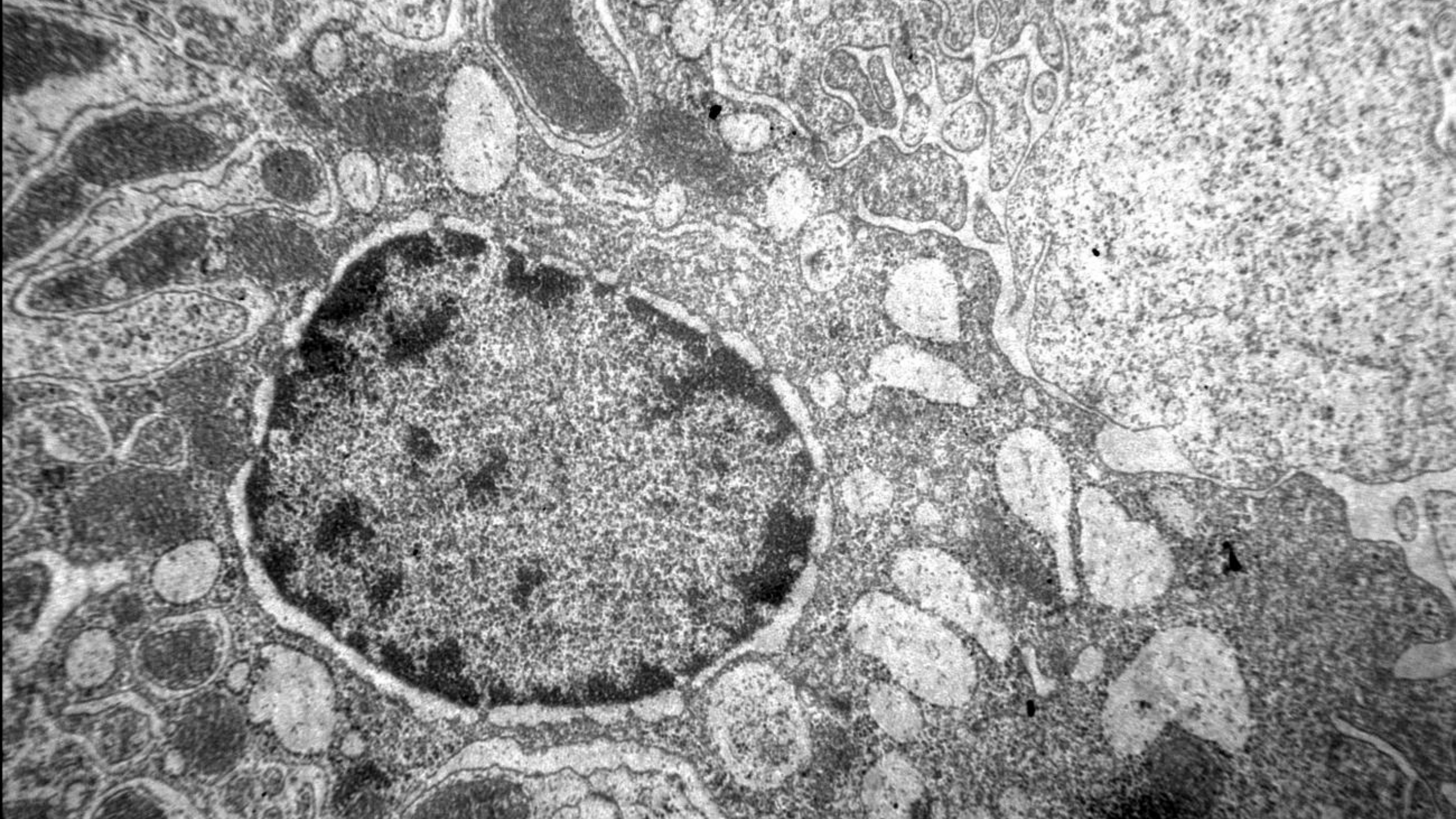


- Examination of ultrathin (30nm) sections of non-osmicated, stain-free pancreatic tissue sections by low-voltage electron microscopy revealed the existence of granules with non-homogeneous matrix and sub-compartments having circular or oval profiles of different electron densities and sizes.

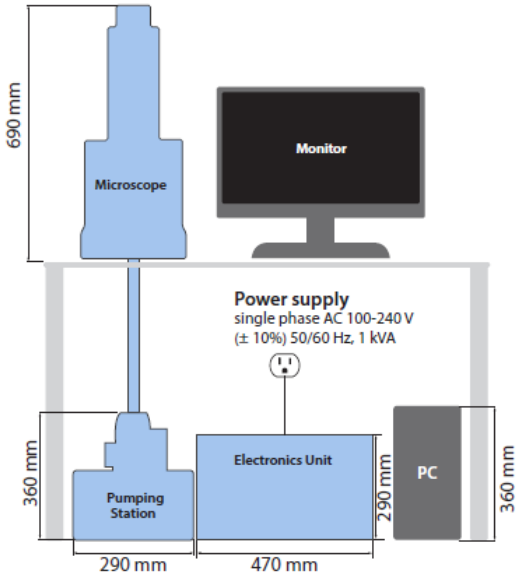


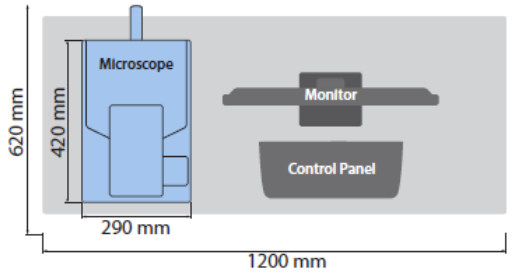
- Crysalins - a new class of protein-based materials
- Staining the proteins interferes with lattice self-assembly

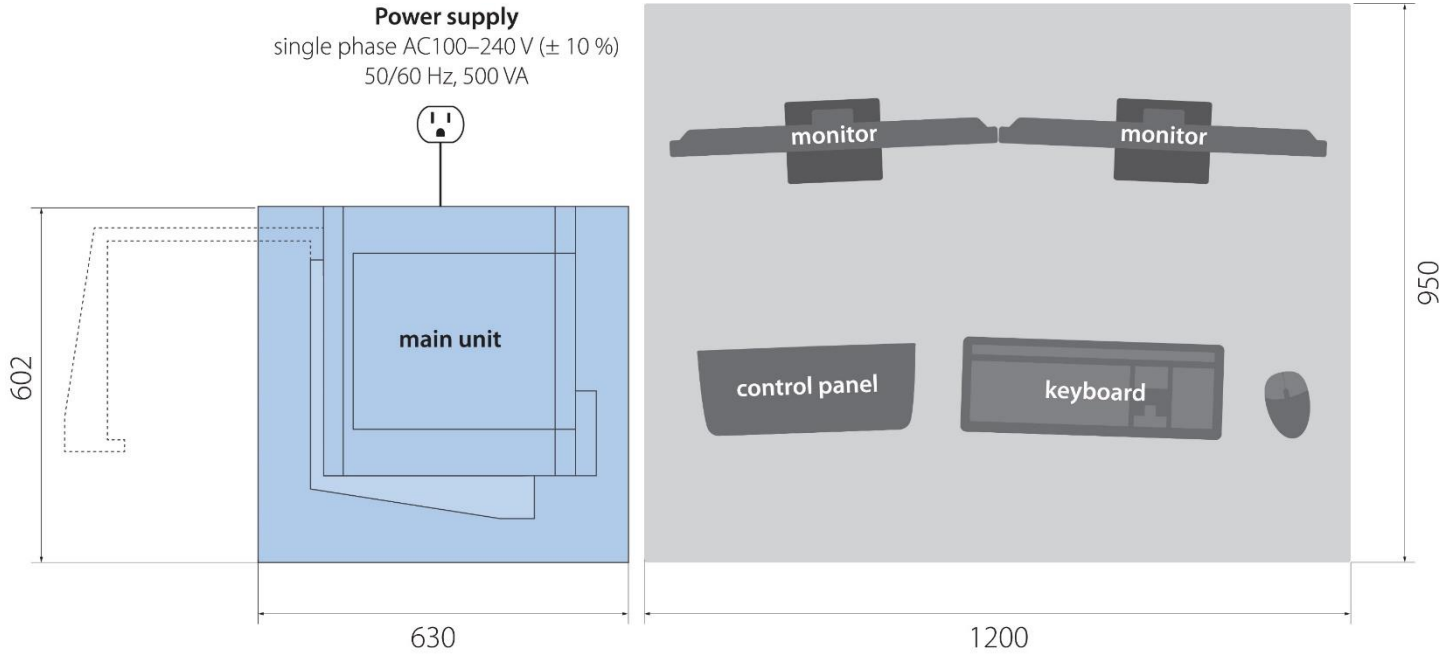




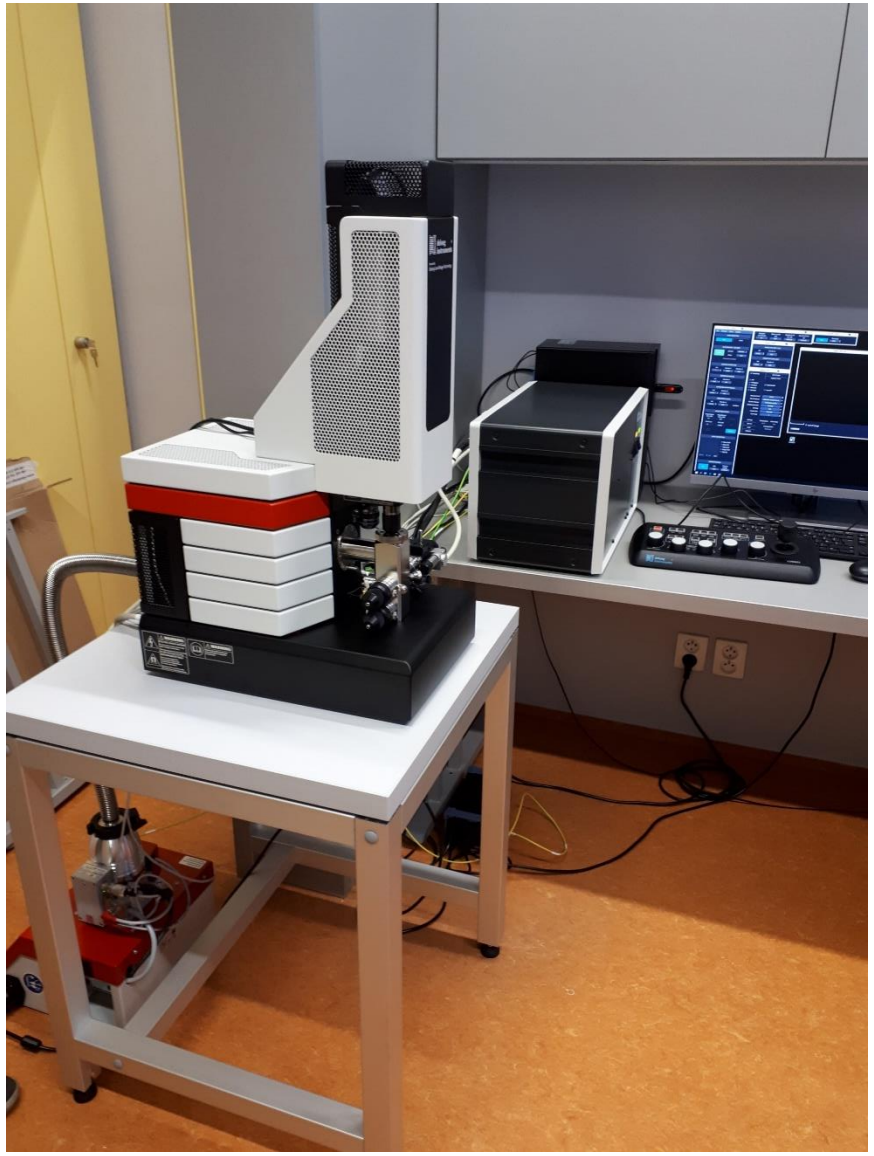
Where LVEMs Help

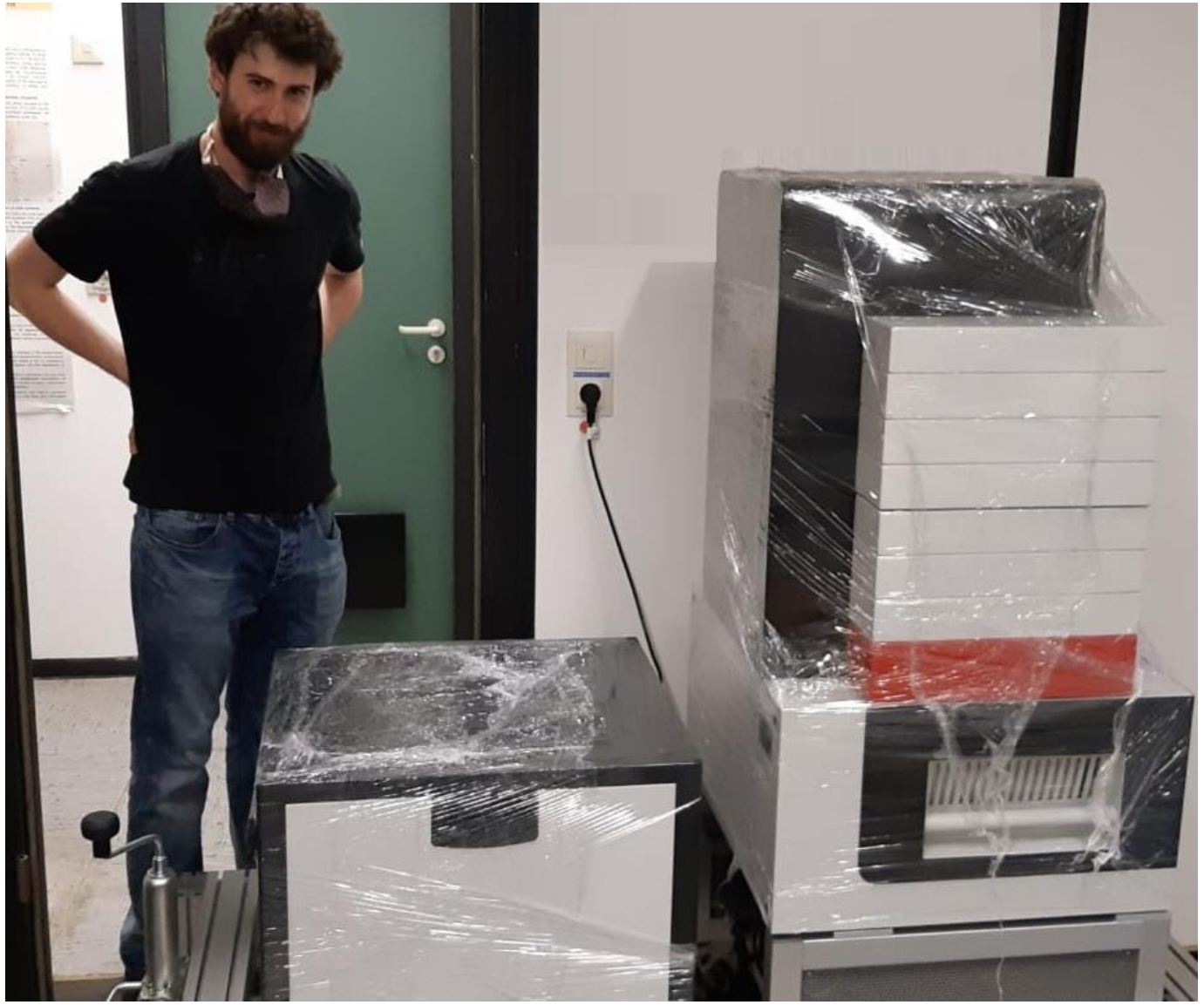






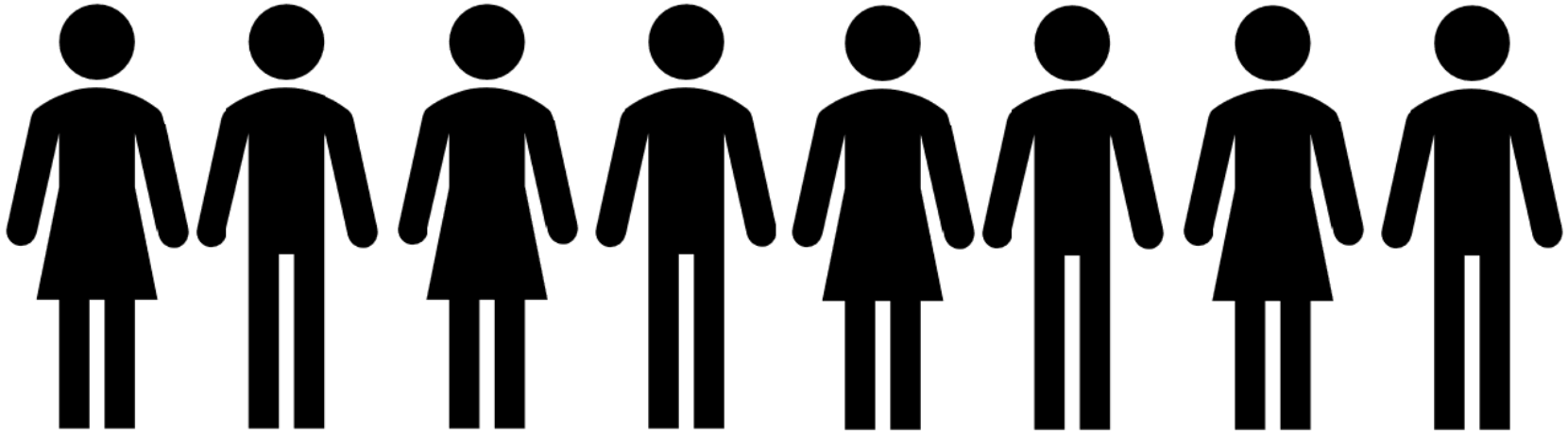
Where LVEMs Help



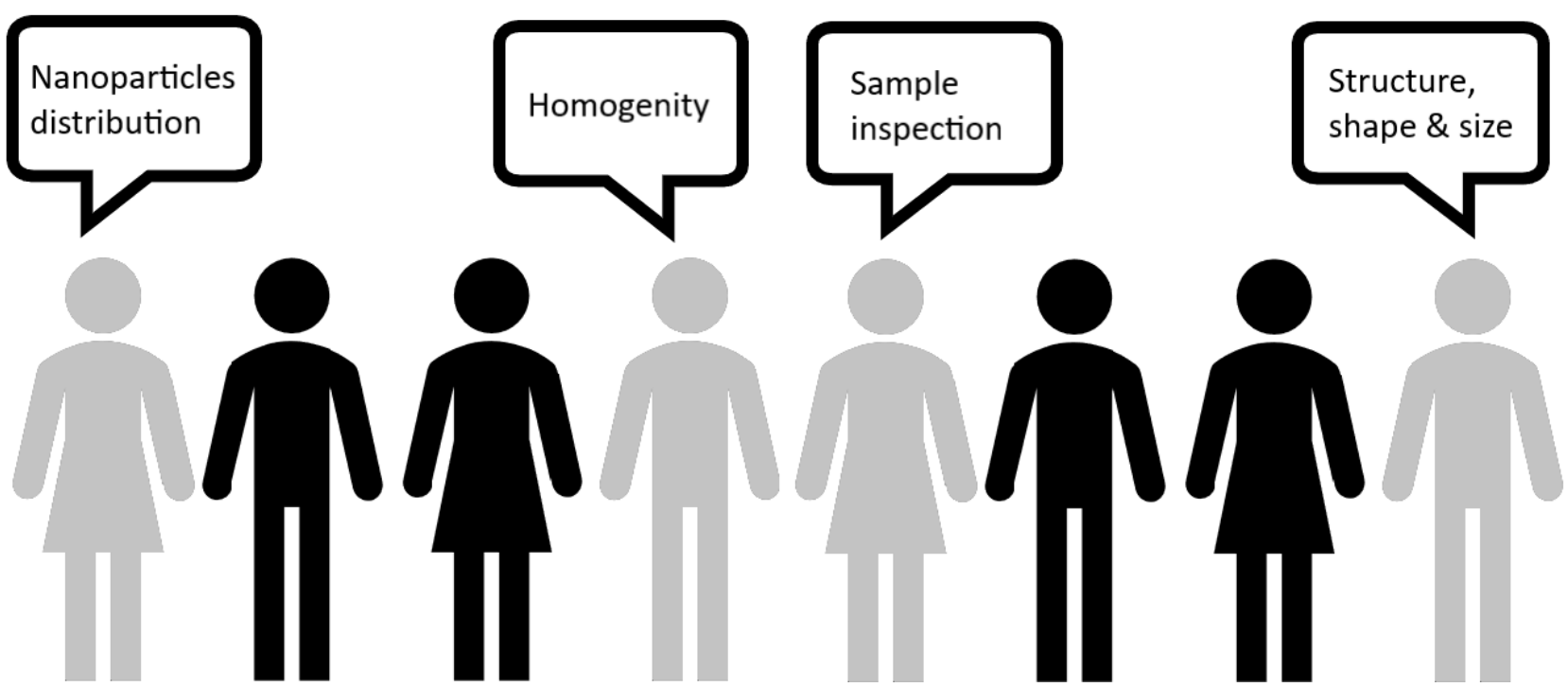


Where LVEMs Help

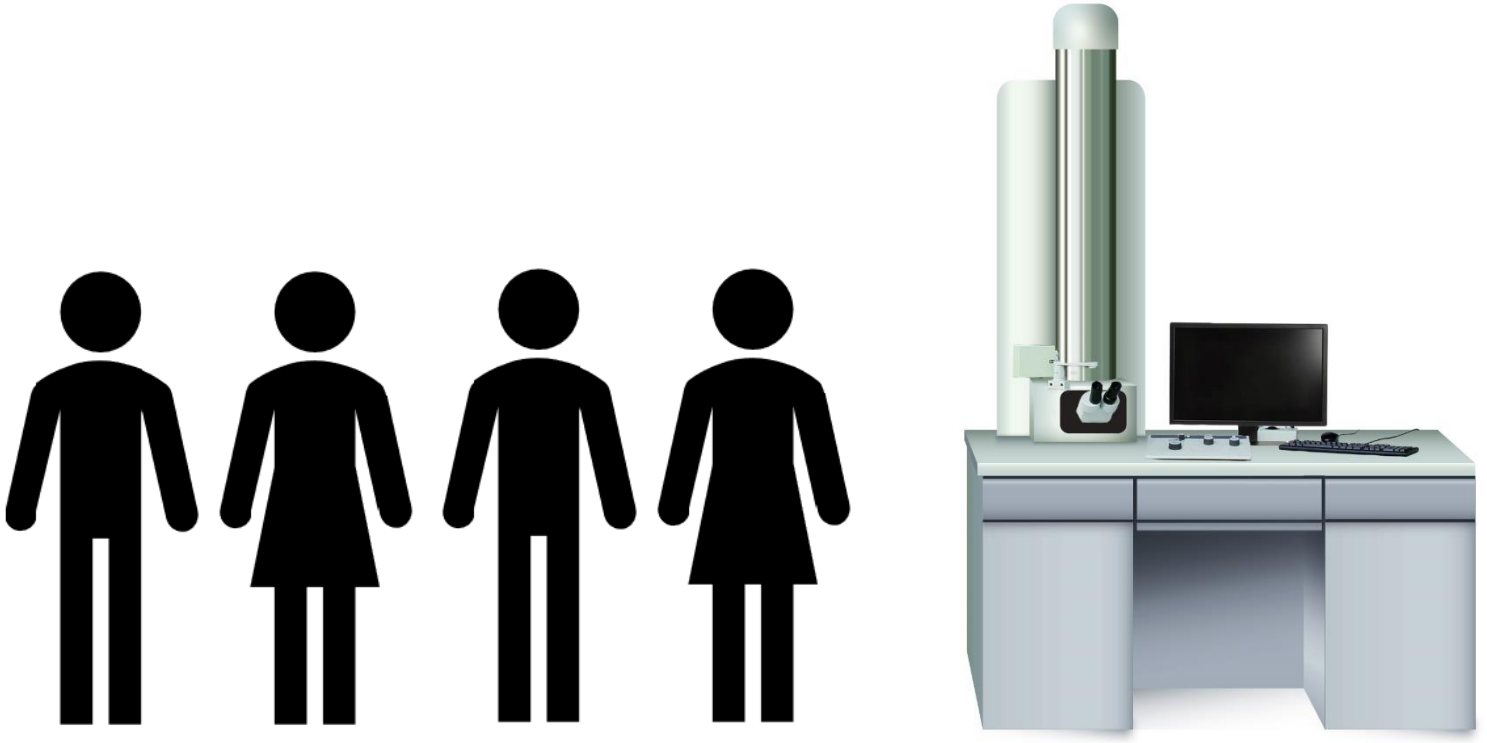
Where LVEMs Help



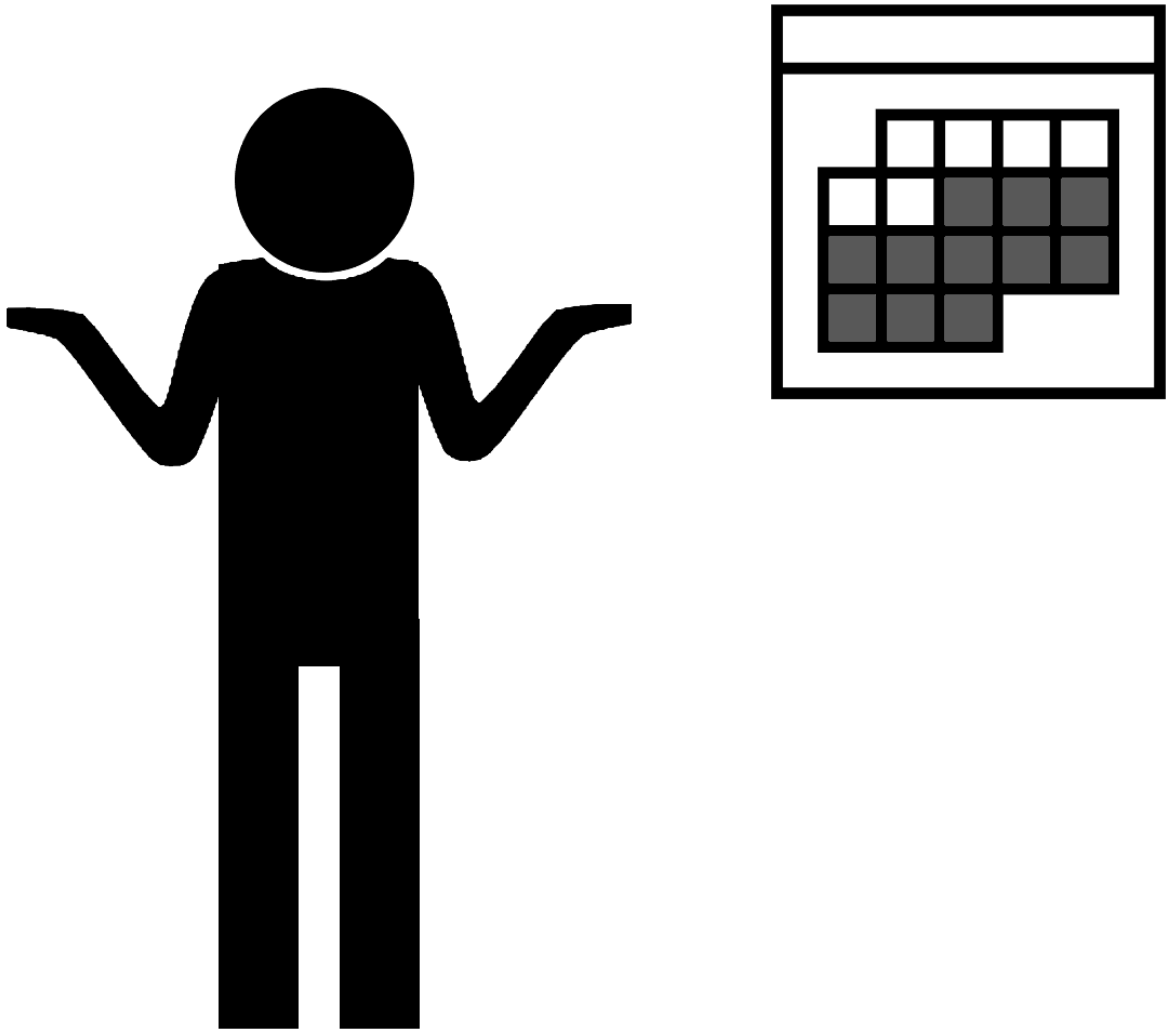
Where LVEMs Help



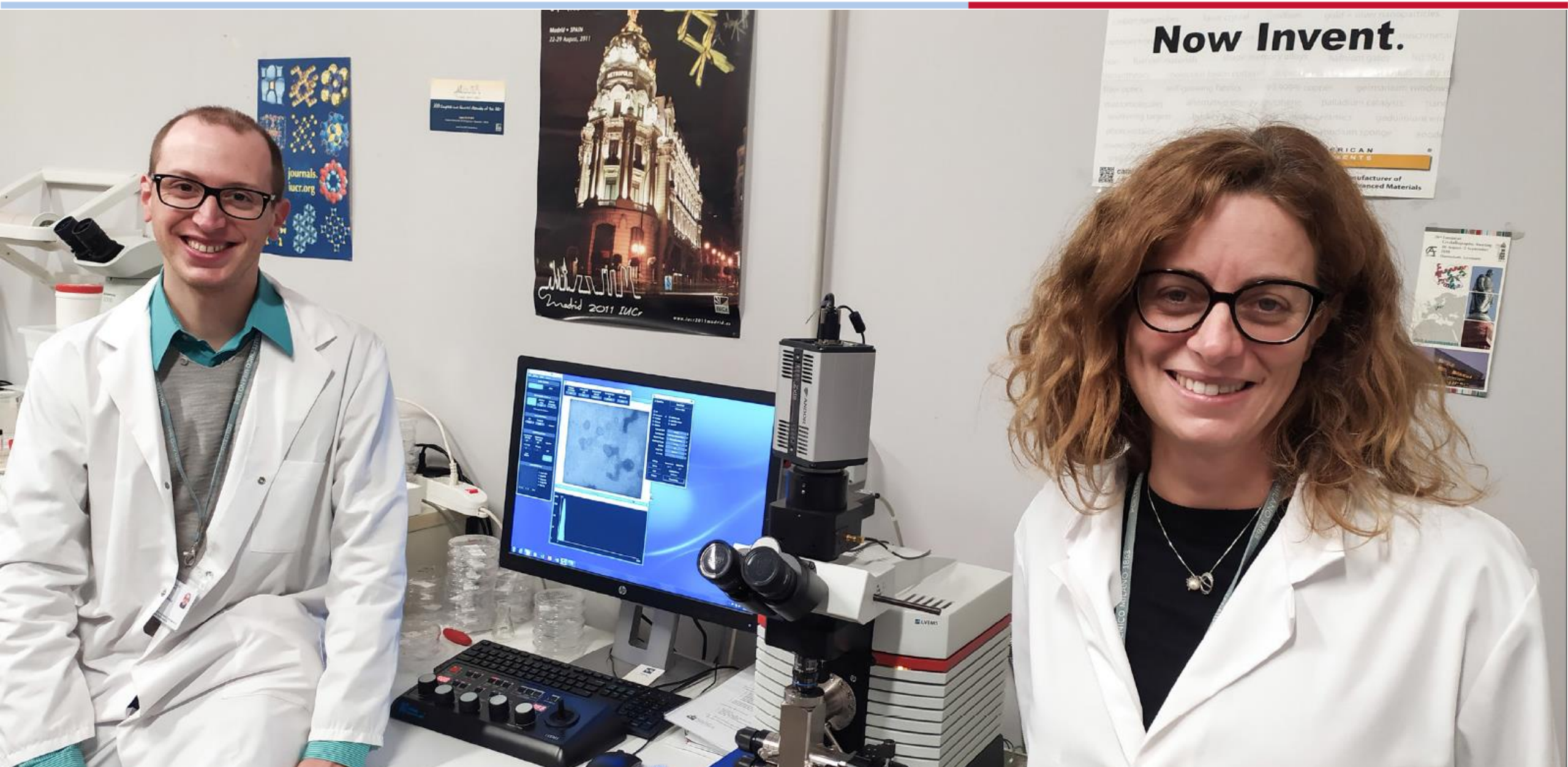
Where LVEMs Help



Where LVEMs Help



Where LVEMs Help



Where LVEMs Help

- When you need naturally high contrast, even without staining
- If you need a TEM and have so little space
- In case you need a robust instrument for students
- When you need to redirect the routine tasks from an overloaded big TEM
- If you need a TEM at hand for your research

Let's talk about LVEM

入江株式会社

入江株式会社【大阪支店】石田亮介
TEL: 06-6352-6673 Mail: ishida@irie.co.jp

FITリーディンテックス株式会社

入江株式会社【計測・光学事業部】紀平高志
TEL: 03-6260-8880 Mail: t.kihira@irie.co.jp

DELONG INSTRUMENTS a.s.
Palackeho trida 3019/153 b
612 00 Brno, Czech Republic
www.delong.cz
info@delong.cz